Se	earch	Not	es

_	Application No.	Applicant(s)	
	09/973,617	CHEN, CHIN-LONG	
	Examiner	Art Unit	
	Tan V Mai	2124	

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708	492	8/4/2004	
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INTERFERENCE SEARCHED			
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Double Patenting Check Data Bases Search (see attached copy)	8/4/2004	